

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

10/631,082

Confirmation No. 2031

**Applicant** Filed

Hechtl et al. 07/31/2003

TC/A.U.

**TBD** 

Examiner

**TBD** 

Docket No.

TID-34165

Customer No.

23494

Title

METHOD OF INSPECTING A MASK

## **ART CITE**

**Commissioner for Patents** 

P.O. Box 1450

Alexandria, VA 22313-1450

**MAILING CERTIFICATE** 

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450.

Marianna Smith

11-20-02 Date

Dear Sir:

Please make the references listed on the enclosed PTO-1449 of record under 37 C.F.R. 1.56, 1.97, and 1.98 in the patent application identified above. They were cited in a corresponding German patent application. Copies of the listed references are enclosed.

Respectfully submitted,

Jacqueline J. Garner Attorney for Applicants Reg. No. 36,144

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Approved for use through 10/31/2002. OMB 0651-0031 Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

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./ '6			Application Number	10/631,082			
8			Filing Date	07/31/2003			
NOV 2 4 2003 PH			First Named Inventor	Christoph Hechtl			
			Group Art Unit	TBD			
			Examiner Name	TBD			
STEPHADEMARY 1	of	11	Attorney Docket No.	TID-34165			

				U.S	S. PATENT DOCU	MENTS
Exam. Initials		U.S. Patent Document		Name of Patentee	Date of Pub.	
	Cite No.1	Number	Kind Code <sup>2</sup> (if known)	or Applicant of Cited Doc.	of Cited Doc. (mm-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figur Appear
	AA	4,906,326		Amemiya et al.	3/9/1990	
	AB	2002/0024019A1		Matsuoka	2/28/2002	
	AC					
	AD					
	AE					
	AF					
	_AG					
	АН					

					FOREIGN PATE	NT DOCUMENTS		
Exam. Initials*	Cite No.1	Foreign Patent Document			Name of Patentee	Date of Pub.		T
		Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>2</sup> (if known)	or Applicant of Cited Doc.	of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>8</sup>
	BA	DE	689 23 638 T2		Amemiya	01/18/1996		
	ВВ	DE	101 41 422 A1		Matsuoka	05/08/2002		
	ВС	EP	0 334 680 B1		Amemiya	08/02/1995	Abstract	
	BD							
	BE							
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS						
Exam. Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²			
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Other Prior Art/Non-Patent Literature Documents: <sup>1</sup>Unique citation designation number. <sup>2</sup>Applicant is to place a check mark here if English Translation is attached.

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